

Radiation-Hardened Quad 2-Input AND Gate

with cold sparing

1 GENERAL DESCRIPTION

The **AF54RHC08** is a radiation-hardened by design **quad 2-Input AND gate** that is ideally suited for commercial space and other applications demanding radiation tolerance and high reliability. It is fabricated in a 180 nm CMOS process utilizing proprietary radiation-hardening techniques, delivering high resiliency to single-event effects (SEE) and to a total ionizing dose (TID) up to **300 krad (Si)**.

This device is a member of the Apogee Semiconductor **AF54RHC logic family** operating across a voltage supply range of **1.65 V to 5.5 V**.

Zero-power penalty™ cold sparing is supported, along with Class 1C ESD protection on all inputs and outputs. A proprietary output stage and robust power-on reset (POR) circuit allow the AF54RHC08 to be cold-spared in any redundant configuration with no static power loss on any pad of the device. The redundant output stage also features a high drive capability with low static power loss.

The AF54RHC08 also features a triple-redundant design throughout its entire circuitry, which allows it to be immune to single-event transients (SET) without requiring additional redundant devices.

This device provides four instances of the Boolean logical function **AND** ($Y = A \cdot B$).

Ordering information may be found in Table 9 on Page 11.

1.1 FEATURES

- 1.65 VDC to 5.5 VDC operation
- Inputs tolerant up to 5.5 VDC at any V_{CC}
- Provides logic-level down translation to V_{CC}
- Extended operating temperature range (-55 °C to +125 °C)
- Proprietary **cold sparing capability** with **zero** static power penalty
- **Built-in triple redundancy** for enhanced reliability
- Internal power-on reset (POR) circuitry ensures reliable power up and power down responses during hot plug and cold sparing operations
- Class 1C ESD protection (1000 V HBM, 500 V CDM)
- TID resilience of **300 krad (Si)**.
- SEL immune to LET of **75 MeV-cm²/mg**
- Meets NASA's ASTM E595 outgassing specification

1.2 LOGIC DIAGRAM

The AF54RHC08 logic function is shown below:

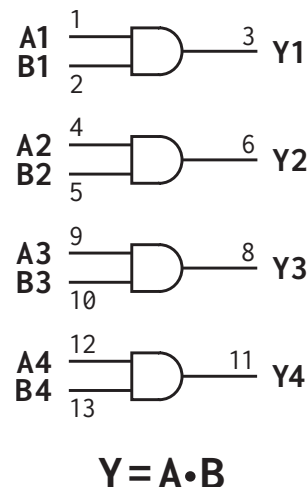


Figure 1: AF54RHC08 Logic Diagram

† See [detailed note](#).

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2 ACRONYMS AND ABBREVIATIONS

ESD	Electrostatic Discharge
POR	Power On Reset
RHA	Radiation Hardness Assurance
SEE	Single Event Effects
SEL	Single Event Latchup
SET	Single Event Transient
TID	Total Ionizing Dose
TMR	Triple Modular Redundancy
CDM	Charged-device Model
HBM	Human-body Model

3 LOGIC DATA

3.1 TRUTH TABLE

The AF54RHC08 truth table is found in Table 1. **H** indicates HIGH logic level and **L** indicates LOW logic level. Subscript **n** reflects one of the four gates in the device (1 to 4).

Table 1: AF54RHC08 Device Truth Table

Input		Output
A _n	B _n	Y _n
L	L	L
L	H	L
H	L	L
H	H	H

4 PIN CONFIGURATION

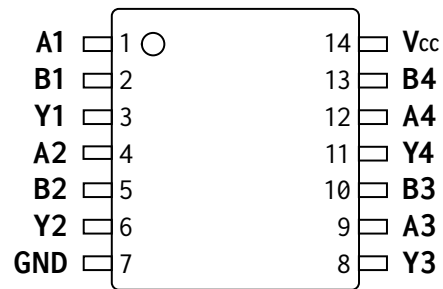


Figure 2: AF54RHC08 Device Pinout

Table 2: AF54RHC08 Device Pinout

PIN NAME(S)	PIN NUMBER(S)	DESCRIPTION
A1, B1 A2, B2 A3, B3 A4, B4	1, 2 4, 5 9, 10 12, 13	Logic Inputs
Y1 Y2 Y3 Y4	3 6 8 11	Logic Outputs
V _{CC}	14	Positive Voltage Supply
GND	7	Ground

5 ELECTRICAL CHARACTERISTICS

The sign convention for current follows JEDEC standards with negative values representing current sourced from the device and positive values representing current sunk into the device.

5.1 ABSOLUTE MAXIMUM RATINGS

Excursions beyond the values listed in Table 3 may cause permanent damage to the device. Proper function of the device cannot be guaranteed if these values are exceeded, and long-term device reliability may be affected. Functionality of the device at these values, or beyond those listed in [Recommended Operating Conditions](#) (Table 4) is not guaranteed.

All parameters are specified across the entire operating temperature range unless otherwise specified.

Table 3: Absolute Maximum Ratings

SYMBOL	PARAMETER	VALUE	UNITS	
V_{CC}	Supply Voltage	-0.5 to +5.5	V	
V_I	Input voltage range	-0.5 to +5.5	V	
V_O	Output voltage range	-0.5 to $V_{CC} + 0.5^{(1)}$	V	
$I_{IK} (V_I < 0)$	Input clamp current	100	mA	
I_O	Continuous output current (per pin)	100	mA	
I_{CC}	Maximum supply current	100	mA	
V_{ESD}	ESD Voltage	HBM	1000	V
		CDM	500	V
T_J	Operating junction temperature range	-55 to +150	°C	
T_{STG}	Storage temperature range	-65 to +150	°C	

⁽¹⁾ V_O must remain below absolute maximum rating of V_{CC}

5.2 RECOMMENDED OPERATING CONDITIONS

All recommended parameters below are specified across the entire operating temperature range unless otherwise specified.

Table 4: Recommended Operating Conditions

SYMBOL	PARAMETER	MIN	MAX	UNITS	
V_{CC}	Supply voltage	1.65	5.5	V	
V_I	Input voltage range	0	5.5	V	
V_O	Output voltage range	0	V_{CC}	V	
V_{IH}	HIGH-level input voltage	$V_{CC} = 1.65$ to 1.95 V	1.4	-	V
		$V_{CC} = 2.3$ to 2.7 V	1.9	-	
		$V_{CC} = 3.0$ to 3.6 V	2.5	-	
		$V_{CC} = 4.5$ to 5.5 V	3.8	-	
V_{IL}	LOW-level input voltage	$V_{CC} = 1.65$ to 1.95 V	-	0.4	V
		$V_{CC} = 2.3$ to 2.7 V	-	0.6	
		$V_{CC} = 3.0$ to 3.6 V	-	0.9	
		$V_{CC} = 4.5$ to 5.5 V	-	1.35	
I_{OH}	HIGH-level output current	$V_{CC} = 1.65$ to 1.95 V	-	-4	mA
		$V_{CC} = 2.3$ to 2.7 V	-	-8	
		$V_{CC} = 3.0$ to 3.6 V	-	-16	
		$V_{CC} = 4.5$ to 5.5 V	-	-24	
I_{OL}	LOW-level output current	$V_{CC} = 1.65$ to 1.95 V	-	4	mA
		$V_{CC} = 2.3$ to 2.7 V	-	8	
		$V_{CC} = 3.0$ to 3.6 V	-	16	
		$V_{CC} = 4.5$ to 5.5 V	-	24	
t_r, t_f	Input rise or fall time (10% - 90%)	$V_{CC} = 1.65$ to 1.95 V	-	1000	ns
		$V_{CC} = 2.3$ to 2.7 V	-	600	
		$V_{CC} = 3.0$ to 3.6 V	-	500	
		$V_{CC} = 4.5$ to 5.5 V	-	400	

Table 5: Thermal Information

SYMBOL	PARAMETER	MIN	TYP	MAX	UNITS
T_J	Operating junction temperature	-55	-	+125	°C
$R_{\theta JA}$	Junction to ambient thermal resistance	-	100	-	°C/W

5.3 STATIC CHARACTERISTICS

All parameters are specified across the entire operating temperature range unless otherwise specified.

Table 6: DC Electrical Characteristics

SYMBOL	PARAMETER	CONDITIONS	V _{CC}	MIN	TYP	MAX	UNITS
V _{OL}	LOW-Level Output Voltage	I _O = 100 μA	1.65 to 5.5 V	-	0.02	0.05	V
		I _O = 1 mA	1.65 to 5.5 V	-	0.05	0.15	V
		I _O = 4 mA	1.65 V	-	0.27	0.8	V
			2.3 V	-	0.3	0.6	V
			3.0 V	-	0.2	0.4	V
			4.5 V	-	0.2	0.4	V
		I _O = 8 mA	2.3 V	-	0.6	1.0	V
			3.0 V	-	0.4	0.8	V
			4.5 V	-	0.3	0.6	V
		I _O = 16 mA	3.0 V	-	1.0	1.4	V
			4.5 V	-	1.1	1.2	V
		I _O = 24 mA	4.5 V	-	1.1	1.5	V
		V _{OH}	HIGH-Level Output Voltage	I _O = -100 μA	1.65 to 5.5 V	V _{CC} - 0.1	V _{CC} - 0.02
I _O = -1 mA	1.65 to 5.5 V			V _{CC} - 0.15	V _{CC} - 0.08	-	V
I _O = -4 mA	1.65 V			1	1.35	-	V
	2.3 V			1.8	2.0	-	V
	3.0 V			2.6	2.8	-	V
	4.5 V			4.2	4.4	-	V
I _O = -8 mA	2.3 V			1.4	1.7	-	V
	3.0 V			2.2	2.5	-	V
	4.5 V			3.9	4.1	-	V
I _O = -16 mA	3.0 V			1.5	2.0	-	V
	4.5 V			3.3	3.8	-	V
I _O = -24 mA	4.5 V			3.0	3.5	-	V
I _{CC}	Quiescent supply current			V _I = V _{CC} or GND I _O = 0 mA	5.5 V	-	130
I _I	Input current	V _I = V _{CC} or GND	1.65 to 5.5 V	-	-	±8	μA
I _{OFF}	Powerdown leakage current ⁽¹⁾	V _I = V _{CC} or GND	OFF ⁽²⁾	-	-	8	μA

⁽¹⁾ into any input or output port

⁽²⁾ V_{CC} is at GND potential

5.4 DYNAMIC CHARACTERISTICS

All parameters are specified across the entire operating temperature range unless otherwise specified.

Table 7: AC Electrical Characteristics

SYMBOL	PARAMETER	CONDITIONS	V _{CC}	MIN	TYP	MAX	UNITS
$t_{pd}^{(1)}$	Propagation Delay (Input A_n or B_n to output Y)	$C_L = 50 \text{ pF}$	4.5 to 5.5 V	-	7.6	11	ns
			3.0 to 3.6 V	-	9	13	ns
			2.3 to 2.7 V	-	11	15	ns
			1.65 to 1.95 V	-	17	25	ns
C_{in}	Input Capacitance ⁽²⁾	$V_I = V_{CC}$ or GND	1.65 to 5.5 V	-	2	4	pF
C_{pd}	Power Dissipation Capacitance ⁽²⁾	$I_o = 0 \text{ mA}$ $f = 1 \text{ MHz}$	5.5 V	-	40	-	pF

⁽¹⁾ equivalent to t_{PLH} , t_{PHL}

⁽²⁾ guaranteed by design

5.5 RADIATION RESILIENCE

For detailed radiation testing reports, please contact Apogee Semiconductor at sales@apogeesemi.com.

Table 8: Radiation Resilience Characteristics

PARAMETER	CONDITIONS	VALUE	UNITS
Total Ionizing Dose (TID)	Please contact Apogee Semiconductor for test report.	300	krad (Si)
SEL Onset LET Threshold	Please contact Apogee Semiconductor for test report.	≥ 75	MeV-cm ² /mg

5.6 CHARACTERISTICS MEASUREMENT INFORMATION

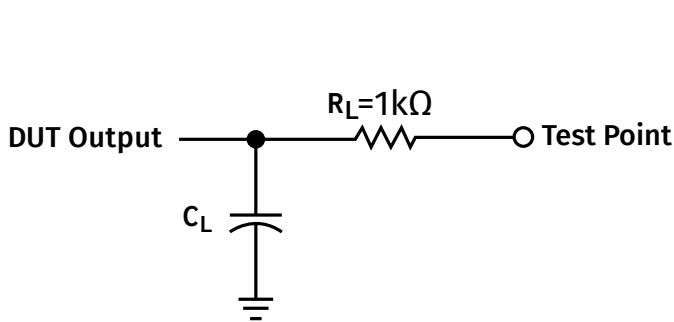


Figure 3: Load Circuit

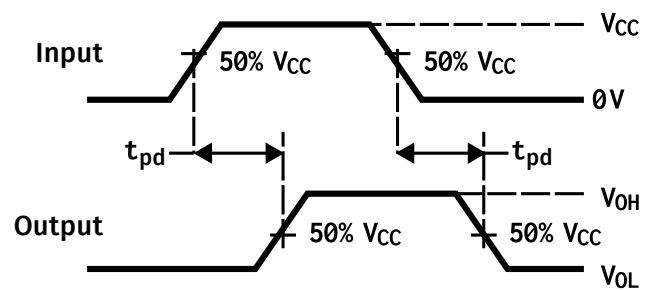


Figure 4: Propagation Delay Measurement

6 DETAILED DESCRIPTION

The AF54RHC08 is a quad 2-Input AND gate intended to perform the Boolean function **AND** ($Y = A \cdot B$) in positive logic. Designed to operate from a wide supply voltage of 1.65 to 5.5 V, it has fully redundant input and output stages providing for superior resiliency to single event effects.

The output and input stages are constructed with transient-activated clamps (Figure 5, 6) that prevent inadvertent biasing of the V_{CC} power rail through parasitic diodes inherent to conventional input, output, and ESD circuits. The IC also incorporates an internal power-on reset (POR) circuit that prevents the output from driving erroneous results during power-on, and guarantees correct operation at power supply voltages as low as 1.65 V. While the supply is ramping, the POR holds the output buffers in tri-state, a feature that prevents unwanted DC current during cold sparing on input and output pins.

The AF54RHC family's I/O protection circuitry allows for cold sparing configurations as it avoids a leakage current penalty on inputs and outputs while in a power-down state. This can result in considerable power savings in systems where multiple-path redundancy is employed. The ESD clamp circuits for this logic family are designed to support Class 1C ESD levels of 1 kV HBM and 500 V CDM.

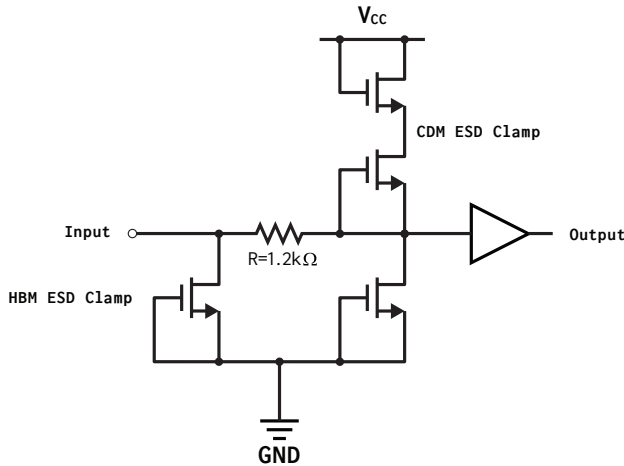


Figure 5: Input Pin Structure

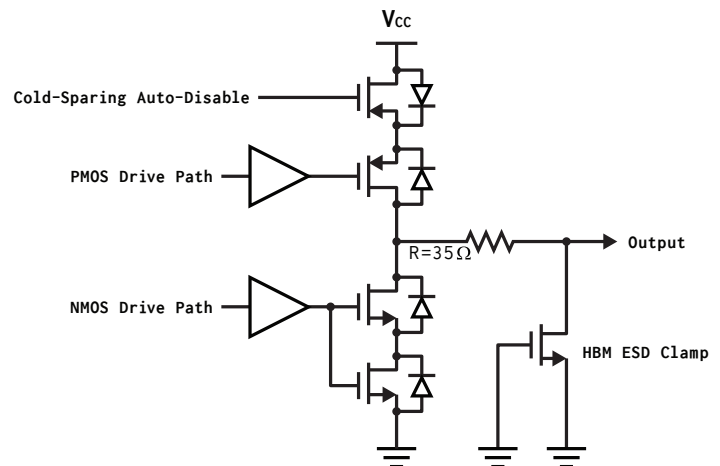


Figure 6: Output Pin Structure

7 APPLICATIONS INFORMATION

7.1 USE IN COLD-SPARING CONFIGURATION

As the AF54RHC family is radiation-hardened by design and includes internal TMR, it can be utilized in high-reliability applications without additional supporting circuitry or devices. Nonetheless, some application requirements call for fully-redundant designs, where an “A” and a “B” device are required, often on separate power rails.

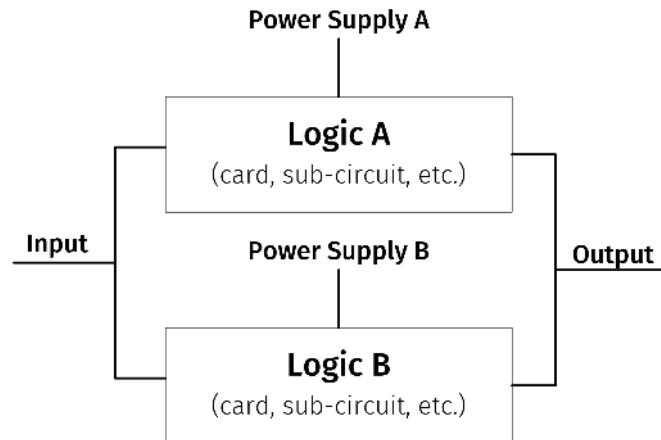


Figure 7: Two-Path Cold-Sparing Configuration

With the cold sparing capability of the AF54RHC family, fully redundant “A” and “B” functions may be placed in parallel (as seen in Figure 7) running off redundant power supplies. The inputs and outputs on each one of these functions are assumed to be based on the AF54RHC family, allowing for direct parallel connection without unwanted leakage current paths during cold sparing. In the event of a failure in power supply A or within function A, the system can simply shut power supply A off and switch on power supply B, without requiring additional input or output switching or configuration changes.

7.2 POWER SUPPLY RECOMMENDATIONS

This device can operate at any voltage within the range specified in [Table 4 Recommended Operating Conditions](#).

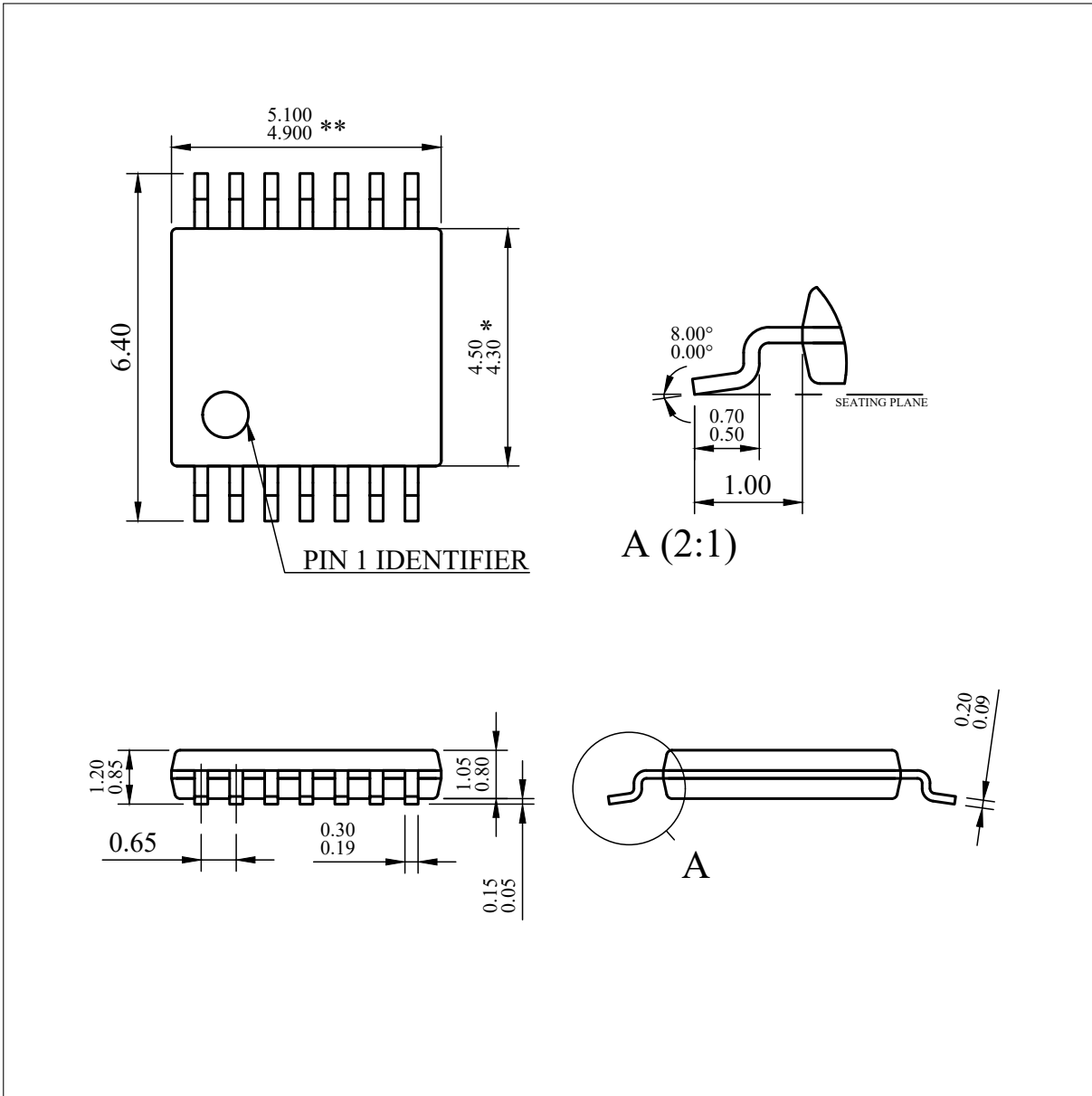
At a minimum, a 16 VDC (or higher), X7R-rated 0.1 μF ceramic decoupling capacitor should be placed near (within 1 cm) the V_{CC} pin of the device.

7.3 APPLICATION TIPS

Unused **inputs** must **not** be left floating. They may be connected to either a low (GND) or high (V_{CC}) bias to provide a known state at the input of the device. Resistors may be used to tie off unused inputs. In the event of a design change, such resistors can be removed, thereby allowing use of the inputs without having to cut traces on the PCB.

An unused **output** may be left floating. It is suggested that it be routed to a test point or similar accessible structure in case the gate needs to be utilized as part of a design revision.

8 PACKAGING INFORMATION



Notes:

1. All linear dimensions are in millimeters. Dimensioning and tolerancing are as per ISO/TS 128-71:2010
2. The part is compliant with JEDEC MO-153 specifications.

* Body width does **not** include interlead flash. Interlead flash shall not exceed 0.25 mm each side.

** Body length does **not** include mold flash, protrusion, or gate burrs. Mold flash, protrusions, and gate burrs shall not exceed 0.15 mm on each side.

Figure 8: Package Mechanical Drawing

9 ORDERING INFORMATION

Example part numbers for the AF54RHC08 are listed in Table 9. The full list of options for this part can be found in Figure 9. For a detailed description of product grades, please refer to [Product Grades and Quality Flows document](#). Please contact Apogee Semiconductor sales at sales@apogeesemi.com for further information on sampling, lead time and purchasing on specific part numbers.

Table 9: AF54RHC08 Ordering Information

DEVICE	DESCRIPTION	PACKAGE	LEAD FINISH	PACKAGE DIAGRAM	PACKAGE MASS
AF54RHC08ANT-R	Rad-Hard Quad 2-Input AND Gate (300 krad (Si))	TSSOP-14	NiPdAu	14-NT	58 mg
AF54RHC08ANT-J ⁽¹⁾	Rad-Hard Quad 2-Input AND Gate (300 krad (Si))	TSSOP-14	NiPdAu	14-NT	58 mg
AF54RHC08BNT-R	Rad-Hard Quad 2-Input AND Gate (300 krad (Si))	TSSOP-14	NiPdAu	14-NT	58 mg
AF54RHC08BNT-J ⁽¹⁾	Rad-Hard Quad 2-Input AND Gate (300 krad (Si))	TSSOP-14	NiPdAu	14-NT	58 mg
AF54RHC08CNT-R	Rad-Hard Quad 2-Input AND Gate (300 krad (Si))	TSSOP-14	NiPdAu	14-NT	58 mg
AF54RHC08CNT-J ⁽¹⁾	Rad-Hard Quad 2-Input AND Gate (300 krad (Si))	TSSOP-14	NiPdAu	14-NT	58 mg
AF54RHC08ENT-R	Rad-Hard Quad 2-Input AND Gate (for eval only)	TSSOP-14	NiPdAu	14-NT	58 mg
AF54RHC08ENT-J ⁽¹⁾	Rad-Hard Quad 2-Input AND Gate (for eval only)	TSSOP-14	NiPdAu	14-NT	58 mg

⁽¹⁾ Available through distributors only.

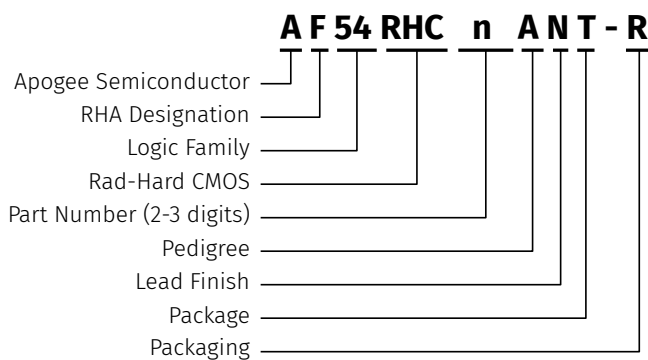


Figure 9: Part Number Decoder

- RHA Designation
 - P** 30 krad (Si)
 - F** 300 krad (Si)
- Part Number
 - _** 08 (Quad 2-Input AND Gate)
- Pedigree
 - A** -55 to +125 °C (Burn-in)
 - B** -55 to +125 °C (No burn-in)
 - C** 25 °C (No burn-in)
 - E** 25 °C Functional Test Only (Evaluation)
- Lead Finish
 - N** Nickel-Palladium-Gold (NiPdAu)
- Package
 - T** 14-pin Thin Shrink Small Outline Package (TSSOP)
- Packaging
 - R** Tape and Reel⁽¹⁾
 - J** JEDEC Tray

⁽¹⁾ [Contact us](#) for custom reel quantities. Orders less than full reel quantities may be shipped as cut tape.

10 REVISION HISTORY

Table 10: Revision History

REVISION	DESCRIPTION	DATE
A02	SEL onset threshold was corrected from ≥ 80 MeV-cm ² /mg to ≥ 75 MeV-cm ² /mg. Updated ordering information. Clarified datasheet release statuses and their definitions.	2025-09-11
A01	Slight wording change in General Description. Updated V _{ESD} HBM value in Absolute Maximum Ratings (Table 3). Updated I _{CC} typ. and max. values, I _I max. value, I _{OFF} max. value, and V _{OH} value in DC Electrical Characteristics (Table 6). Updated t _{pd} values in AC Electrical Characteristics (Table 7).	2025-03-26
A00	Initial internal release.	2025-02-21

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11 LEGAL

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[†] DATASHEET RELEASE STATUS DEFINITIONS

This datasheet is labeled with its status on the cover and at the top of each page to indicate specification maturity and the likelihood of change. The definitions below explain what each label means:

1. **Preliminary** — Created during product design and early development. Provides initial specifications, anticipated performance metrics, and other critical data used to gather targeted customer feedback. Specifications are based on design intent and simulation and may include limited early lab data. Specifications are subject to change, and TBD values may be present.
2. **Pre-production** — Status at the time of E grade release to market. Specifications are supported by simulation and initial device characterization, with few to no TBDs. Limits are not yet finalized and may change prior to Production release.
3. **Production** — Status at the time of flight grade release to market. Final, controlled datasheet with confirmed specifications, performance metrics, and compliance information verified through qualification and production test. Any future specification updates will follow the formal PCN process.